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Cascade Double-sided VCSEL Probe System with Thermally Controlled Probe Unit

> Overview

FormFactor, Inc., a leader in electrical test and measurement, has developed a high precision double-sided and thermally controlled probe system mainly for the VCSEL market.

Triple optics, including LIV (light intensity, current and voltage), near field and far field, can be mounted on top of the prober while probing is done from the bottom side of the wafer. The double-sided chuck design allows free access to both sides of the wafer. The wafer itself can be fixed by vacuum or mechanically clamped to allow testing up to the substrate edge.

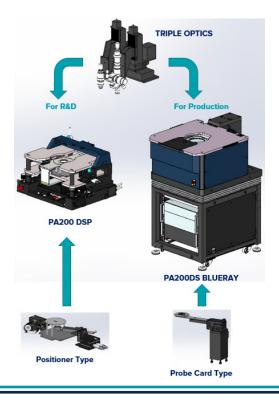
The patented design of the thermally controlled probe unit (FireProbe) enables the test for both high and low temperature with very stable and accurate conditions. Both probe card and probe positioner types can be chosen for this new technology. Our extensive portfolio of highperformance probes suits most requirements.

There are choices of probe systems: a semi-automated double-sided probe system (PA200DSP) for R&D usage and a semi/fully automated double-sided probe system (PA200DS BlueRay) for production. PA200DSP has more flexibility of customization since there is greater access.

> Features / Benefits

Flexibility	 Prober options (PA200 DSP for R&D and PA200DS BlueRay for production) Options of probe positioners and probe cards with different probe types Large number of accessories available
Optics	 Triple optics (LIV, NFP and FFP) can be mounted on top side of the prober Different configurations of optics are available
Double-side probing	 Customized double-sided chuck design for up to 6-inch wafers Variety of wafer carriers, glass chucks, mechanical edge clamping solutions
Thermal control	 Patented design of probe system enables test temperatures from 10°C to 85°C Accuracy of temperature within ±1°C







> Mechanical Performance

PA200DS BlueRav

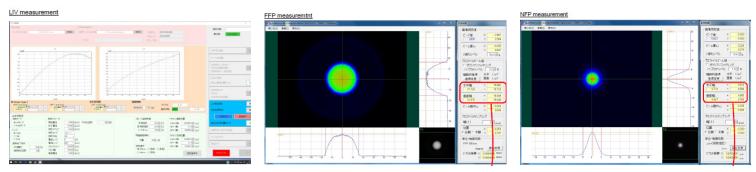
PA200DS BlueRay		PA200DSP		
X-Y Movement		X-Y Movement		
Travel	205 mm x 205 mm	Travel	200 mm x 200 mm	
Resolution	0.5 μm	Resolution	0.5 μm	
Repeatability	± 2 μm	Repeatability / Accuracy	± 1.0 μm / ± 2.5 μm	
Z Movement		Z Movement		
Travel / Resolution	15 mm / 0.25 μm	Travel / Resolution	9 mm / 0.25 μm	
Repeatability	± 1.0 μm	Repeatability	± 1.0 μm	
Theta Movement		Theta Movement		
Travel / Resolution	± 6.0° / 0.0001°	Travel / Resolution	± 6.0° / 0.0001°	

> Optics

LIV			
Spectral Response Range	340 nm to 1100 nm		
CW	1A		
Pulse	5A (500 n sec to 5 m sec	c)	
NFP (M-Scope Type S)	Objective Lens	Measurement Area	Pixel Resolution
High resolution digital CCD detector	50x	0.13x0.1 mm	0.093 μm
		0.06x0.05 m	0.043 μm

InGaAs high sensitivity NIR detector	50x	0.128x0.1024 mm	0.4 μm
	100x	0.064x0.0512 m	0.2 μm
Light irradiation/detection area (size)	Objective lens 10x: equal to the core diameter of 50 μ m in case of fiber core is 50 μ m Objective lens 20x: 1/2 size of the core diameter of 25 μ m in case of fiber core is 50 μ m		

FFP (M-Scope Type F)	Measurement Angle Range	Wavelength Range	Pixel Resolution
High resolution digital CCD detector	Approx. ±40° / N.A. 0.65	400 nm to 1100 nm	Approx. 0.09°
InGaAs high sensitivity NIR detector	Approx. ±39.5° / N.A. 0.65	950 nm to 1700 nm	Approx. 0.4°
Working Distance	Approx. 6 mm ±0.8 mm		



> Probe Card / Positioner

Probe Card	Vertical probes for bump and cantilever probes for pad applications
Positioner	Motorized and manual positioners available with different probe types
Temperature	10°C to 85°C with accuracy of ±1°C

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